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Texas Instruments High Rel Products Reliability Report

Device Type/Device Family: SM320F2812HFGS150

Package Type: 172 / HFG

Wafer Fabrication Facility: Ti Dmos-5

Assembly/Test Facility: Millennium Microtech

Compiled: 07/12

Biased Life Test

Test Method: JESD22-A108 Test Condition: 210°C / 1000 hours

Sample Size: 45 Rejects: 0

Activation Energy (eV): .5
Equivalent Device Hours: 45000
Failure Rate (FIT)*: 20491

^{* 60%} confidence level of random failure rate during nominal 1000 hour life based on test sample size. This not based on wear out failure mechanisms which will begin to affect past the 1000 hr test limit.

| Description | Group B Tests (Wee Condition | kly by Package Family) Referenced Method | Sample Size/Rejects | | | |
|---|------------------------------|---|---------------------|---|--|--|
| B1 Resistance to | | Mil Std 883 | 3/0 | | | |
| Solvents B2 | | Method 2015 | G/ C | * | | |
| Bond strength | Test condition F (FC) | Mil Std 883 Method | 22/0-3/0 | * | | |
| | | 2011/2019/2027 | | | | |
| B3 | | | | | | |
| Solderability | Soldering temperature | Mil Std 883 | 22/0 | | | |
| | of 245C±5 | Method 2003 | | | | |
| Group C Test (Per 3 Month Period by Family) | | | | | | |
| Description C1 | Condition | Referenced Method | Sample Size/Rejects | | | |
| Steady-state life test | 125C/1000Hrs 4.6V | Mil Std 883 Method 1005 | | | | |
| End point electrical | | | 45/0 | * | | |

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| Description D1 | Group D Tests (Ann Condition | nually by Package Family) Referenced Method | Sample Size/Rejects | |
|----------------------------|---------------------------------|--|---------------------|---|
| Physical Dimensions | | Mil Std 883 Method 2016 | 15/0 | * |
| D2 Lead Integrity | | Mil Std 883 Method 2004 & 2028 | 45/0 | * |
| Seal(Fine and Gross) | | Mil Std 883 Method 1014 | 45/0 | * |
| D3 | | Wiction 1014 | | |
| Thermal Shock | -65°C to +150°C 15 cycles | Mil Std 883 Method 1011 | | |
| Temperature Cycle | -65°C to +150°C 100 cycles | Mil Std 883 Method 1010 | | * |
| Moisture Resistance | • | Mil Std 883 Method 1004 | | |
| Seal(Fine and Gross) | | Mil Std 883 | | * |
| Visual examination | | Method 1014 Mil Std 883 | | |
| Visual examination | | Method 1004 &1010 | | |
| End point electrical D4 | | | 15/0 | * |
| Mechanical Shock | | Mil Std 883 | | |
| Variable Freq | | Method 2002 Mil Std 883 | | * |
| Variable Freq | | Method 2007 | | |
| Constant acceleration | | Mil Std 883 | | |
| 0 1 | | Method 2001 | | * |
| Seal | | Mil Std 883 Method 1014 | | ^ |
| Visual Examination | | Mil Std 883 | | |
| | | Method 2009 | | |
| End point electrical D5 | | | 15/0 | * |
| Salt Atmosphere | | Mil Std 883 | | |
| Cool | | Method1009 | | * |
| Seal | | Mil Std 883 Method 1014 | | |
| Visual Examination | | Mil Std 883 | 15/0 | |
| | | Method 1009 | | |
| D6 | | | | |
| Internal Water Vapor | | Mil Std 883 Method1018 | 3/0 | |
| D7 | | | | |
| Adhesion of Lead | | Mil Std 883 | 15/0 | |
| Finish | | Method 2025 | | |

Supplemental Device Characteristics

| Die Revision: | G | Assembly Site: | ALP |
|-----------------|--------------|-------------------|---------|
| Master Die: | C741720G/LDH | Package Type: | HFG |
| Wafer Fab: | DMOS-5 | Pin Count: | 176 |
| Fab Technology: | CMOS | Mold Compound: | Ceramic |
| Fab Process: | F05 | Mount Compound: | JM7000 |
| Process Code: | N/A | Bond: | .7u Au |
| Passivation: | Nitride | Lead Composition: | Kovar |
| Lead Finish: | Au | | |

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